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#	Articles in Journals	available in kB
A1	K.H. Gaukler and R. Schwarzer Verbessertes Verfahren zur Bestimmung des mittleren inneren Potentials aus Reflexions-Kikuchi-Diagrammen. Optik 33 (1971) 215-229	424
A2	K.H. Gaukler and R. Schwarzer Elektronen-Emissions-Mikroskopie (Review article). Messtechnik 81 (1973) 307-316	1.190
A3	J. Hofmeister and R. Schwarzer Zum Einfluß der kristallographischen Orientierung auf den vektoriellen Photoeffekt. Physics Letters 53A (1975) 283-284	501
A4	G.H. Hartmann, H.P. Niemitz, and R.A. Schwarzer Bestimmung des mittleren inneren Potentials von Diamant und von Vanadium-Pentoxid aus Reflexions-Kikuchi-Diagrammen. Optik 44 (1975) 37-43	488
A5	R. Schwarzer Der Einfluß von Loch- und Ringblenden auf die Energieverteilung der Elektronen im Emissions-Elektronenmikroskop. Optik 44 (1975) 61-78	1.078
A6	R. Schwarzer Die Verbesserung des Bildkontrastes im Emissions-Elektronenmikroskop durch eine ringförmige Aperturblende. Optik 44 (1975) 121-131	533
A7	M.B. Trullenque, Z.P. Argüello, and R.A. Schwarzer Investigations of ionic crystals with the photoemission electron microscope. Revista Microscopia Electrónica 3 (1976) 156-157	252
A7a	R.A. Schwarzer, J.I. Cisneros, M. Tomyama, Shih-Lin Chang, and Z.P. Argüello Study of Orientation Contrast and Information Depth in LiF with the Photoemission Electron Microscope (PEEM). Revista de Microscopia Electrónica 5 (1978)	288
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A10	R. Schwarzer Die Bestimmung von Strukturpotentialen aus Kossel-Möllenstedt-Diagrammen an epitaktisch aufgedampften, freitragenden Kupfereinkristallschichten. Optik 54 (1979) 193-199	190
A11	R.A. Schwarzer Emission electron microscopy - A review. Part 1: Basic concepts and applications in physics. Microscopica Acta 84 (1981) 51-86	1.961
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A13	R.A. Schwarzer On-line measurement of foil thickness from Kossel-Möllenstedt diffraction patterns. Optik 77 (1987) 55-56	179
A14	R.A. Schwarzer and H. Weiland Texture analysis by the measurement of individual grain orientations - Electron microscopical methods and application on dual-phase steel. Textures and Microstructures 8&9 (1988) 551-577	1.459

A15	R.A. Schwarzer Measurement of local textures with transmission and scanning electron microscopes. Textures and Microstructures 13 (1990) 15-30	1.502
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A41	K. Helming, R.A. Schwarzer, B. Rauschenbach, S. Geier, B. Leiss, H.-R. Wenk, K. Ullemeyer, and J. Heinitz Texture estimates by means of components. Z. Metallkunde 85 (1994) 545-553	1.627
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A104	R. Schwarzer Orientation microscopy using the analytical scanning electron microscope. Pract. Metallogr. 51 (2014) 160-179	422
A105	R.A. Schwarzer and Jarle Hjelen Backscattered Electron Imaging with an EBSD Detector. Microscopy Today 23 (2015) 12-17	2.062
A106	R. Schwarzer and C. Esling Texture et anisotropie des matériaux polycristallins - Cartographie par diffraction de Kikuchi. Techniques de l'ingénieur - Mise en forme des métaux et fonderie: M3040 V2 (2021) 1-16 & DOC M3040 V2 (2021) 1-3 DOI 10.51257/a-v2-m3040	2.163
A107	C. Esling and R. Schwarzer Texture et anisotropie des matériaux polycristallins - Diffraction RX, rayonnement synchrotron et neutrons. Techniques de l'ingénieur - Mise en forme des métaux et fonderie: M3039 v1 (2022) 1-32 & DOC M3039 v1 (2022) 1-3 DOI 10.51257/a-v1-m3039	(preprint) (5984)
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